What is claimed is:

1. A method of detecting defects during a write operation for an optical disk recording device, comprising:

a. in a short period of time immediately after writing begins:

i. comparing a sub-beam added (SBAD) signal and a reference signal output by a low pass filter having a second threshold frequency, and

ii. identifying a defect when a difference between the SBAD signal and the reference signal exceeds either a second upper limit or a second lower limit; and

b. after the short period of time:

i. comparing the SBAD signal and a reference signal output by the low pass filter having a first threshold frequency, and

ii. identifying a defect when a difference between the SBAD signal and the reference signal exceeds either a first upper limit or a first lower limit;

wherein the second threshold frequency is higher than the first threshold frequency, the second upper limit is greater than the first upper limit, and the second lower limit is less than the first lower limit.

2. The method of claim 1, wherein the short period of time is equal to the time for the first five blocks of a packet write.

3. The method of claim 1, wherein the second threshold frequency, the second upper limit and the second lower limit are maintained for the duration of the short period of time.

4. A method of preventing an optical disk recording device from failing to correctly detect defects during writing, wherein the optical disk recording device has a preset first threshold frequency, a preset first upper limit and a present first lower limit, comprising:

a. starting to write data;

b. increasing the first threshold frequency to a second threshold frequency, increasing the first upper limit to a second upper limit, and decreasing the first lower limit to a second lower limit;

c. allowing a predetermined period of time to pass; and

d. decreasing the second threshold frequency to the first threshold frequency, decreasing the second upper limit to the first upper limit, and increasing the second lower limit to the first lower limit.

5. The method of claim 4, wherein the predetermined period of time is equal to the time for the first five blocks of a packet write.

6. The method of claim 4, further including:

identifying a defect when a difference between a sub-beam added (SBAD) signal and a reference signal exceeds either the second upper limit or the second lower limit.

7. The method of claim 4, further including:

identifying a defect when a difference between a sub-beam added (SBAD) signal and a reference signal exceeds either the first upper limit or the first lower limit.

8. The method of claim 6, further including:

identifying a defect when a difference between a sub-beam added (SBAD) signal and a reference signal exceeds either the first upper limit or the first lower limit.